ICXOM23

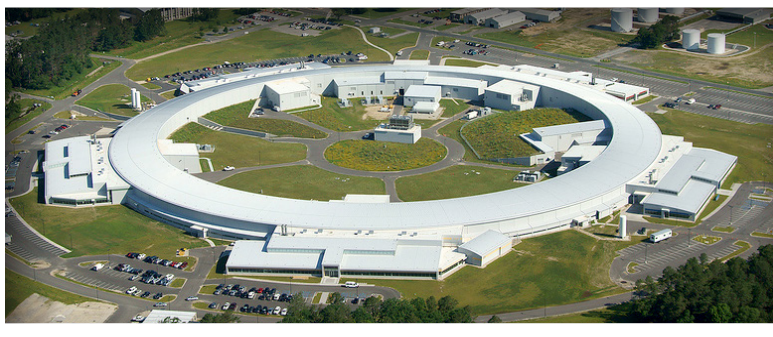
23rd International Congress on X-ray Optics and Microanalysis

September 14-18, 2015

Brookhaven National Laboratory

Long Island, New York

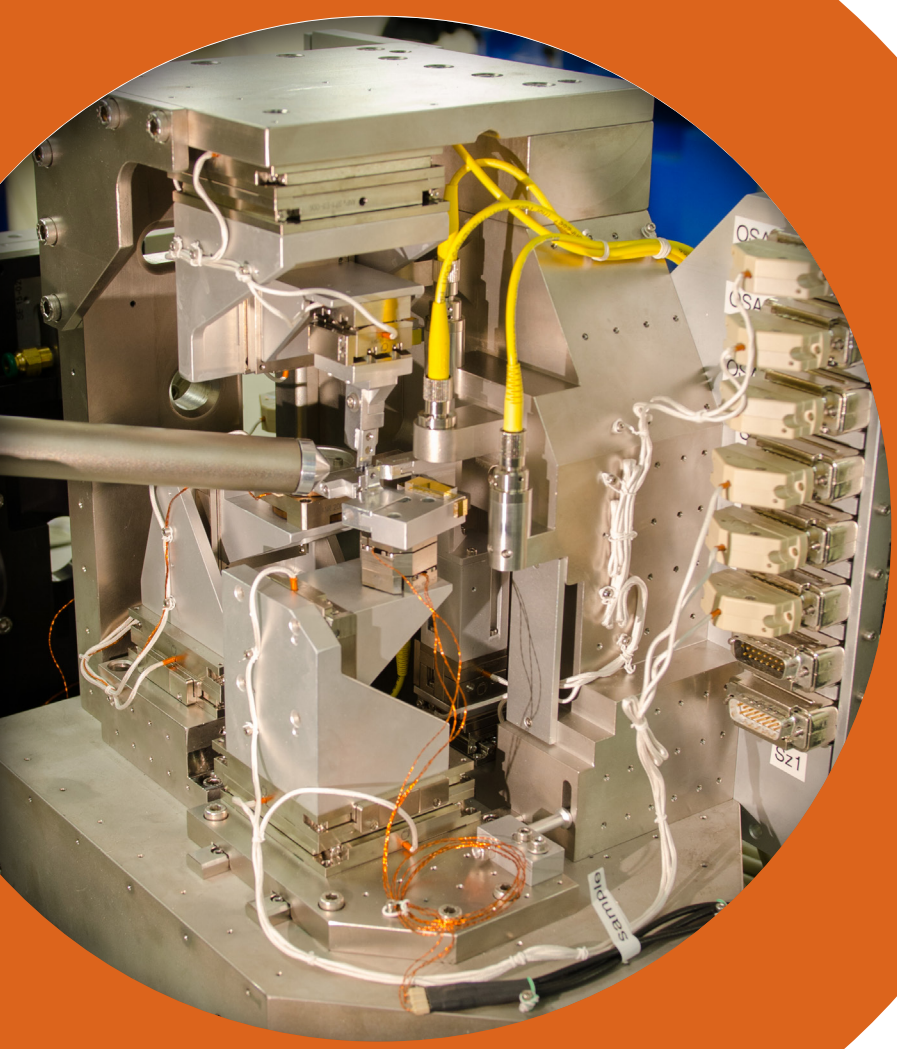
ICXOM23 will bring together scientists in the fields of x-ray microanalysis and those involved in optical instrumentation developments which will extend the reach of microanalysis. Although synchrotron radiation will be at the heart of the conference, since electron microscopy offers a different view of materials, the conference also welcomes contributions of recent developments in that field.



The conference will be held at Brookhaven National Laboratory on Long Island in New York State. The laboratory is host to the National Synchrotron Light Source and its successor, NSLS-II, pictured above (*http://www.bnl.gov/ps/*). BNL is also home to a new nanoscience center (*http://www.bnl.gov/cfn/*) and a state-of-the-art aberration-compensated TEM facility (*http://www.bnl.gov/cfn/facilities/microscopy.php*, *http://www.bnl.gov/tem/*).

Topics

Optics for microanalysis
Scanning microscopy
Full-field imaging
Coherent Imaging
PEEM
Electron microscopy
Microdiffraction
Data analysis
Detectors



Conference Chairs

Peter Siddons (BNL)
Juergen Thieme (BNL)

Organizers

Yong Chu (BNL)
Gretchen Cisco (BNL)
Andrei Fluerasu (BNL)
Mourad Idir (BNL)
Qun Shen (BNL)
Lutz Wiegart (BNL)
Nancye Wright (BNL)
Hanfei Yan (BNL)
Yimei Zhu (BNL)
Paul Zschack (BNL)

Registration to open on January 15, 2015

Early registration deadline:
July 1, 2015

General registration deadline:
September 1, 2015

Abstract deadline:
April 30, 2015

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http://www.bnl.gov/icxom23

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Argonne NATIONAL LABORATORY
BROOKHAVEN NATIONAL LABORATORY
CXRO THE CENTER FOR X-RAY OPTICS
SLAC NATIONAL ACCELERATOR LABORATORY